

<b>Notice of References Cited</b>	Application/Control No. 10/619,046	Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Khai M. Nguyen	Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,577,871 B1	06-2003	Budka et al.	455/453
*	B	US-2002/0102976 A1	08-2002	Newbury et al.	455/436
*	C	US-6,212,389 B1	04-2001	Fapojuwo, Abraham O.	455/453
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.